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CLAIMS:

1. A dielectric composition comprising a mixture of:

- a ceramic composition containing  $Ba_aRE_bTi_cO_3$ , wherein RE represents a rare earth element, with  $0.05 \le a \le 0.25$ ,  $0.525 \le b \le 0.70$ ,  $0.85 \le c \le 1.0$ , and 2a + 3b + 4c = 6, and free from lead and bismuth,
- a glass composition comprising SiO<sub>2</sub>, a bivalent metal oxide chosen from the group consisting of MgO and ZnO and at least 10% by weight with respect to the glass composition of a further metal oxide chosen from the group consisting of Li<sub>2</sub>O and TiO<sub>2</sub>, and a metal oxide which is different from the bivalent metal oxide present in the glass composition.

2. A dielectric composition as claimed in Claim 1, characterized in that the metal oxide in the dielectric composition is an oxide of a metal chosen from the group consisting of magnesium, zinc, copper, manganese, cobalt, iron, nickel, erbium, holmium, indium, dysprosium, tungsten and yttrium.

- 3. A dielectric composition as claimed in Claim 1, characterized in that the further metal oxide in the glass composition is Li<sub>2</sub>O.
- A dielectric composition as claimed in Claim 3,
  characterized in that the glass composition essentially consists of 50-80% by weight of SiO<sub>2</sub>,
  5-25% by weight of at least one alkaline earth metal oxide including MgO, and 10-25% by weight of Li<sub>2</sub>O, and in that it is substantially free from boron.
- 5. A dielectric composition as claimed in Claim 4, characterized in that the alkaline earth metal oxide is primarily MgO.
  - 6. A dielectric composition as claimed in Claim 1, characterized in that the bivalent metal oxide in the glass composition is ZnO, and in that the further metal oxide is TiO<sub>2</sub>.

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7. A dielectric composition as claimed in Claim 1, 3, 4 or 6, characterized in that the glass composition is present in an amount of 3 to 5% by weight with respect to the ceramic composition.

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8. A method of manufacturing a ceramic multilayer element comprising the steps of

manufacturing a multilayer stack comprising a first ceramic foil, a first electrode comprising Cu, a second ceramic foil, and a second electrode comprising Cu, which ceramic foils are manufactured from a dielectric composition comprising a ceramic composition and a glass composition comprising  $SiO_2$ , which ceramic composition contains  $Ba_aRE_bTi_cO_3$ , wherein RE represents a rare earth element, with  $0.05 \le a \le 0.25$ ,  $0.525 \le b \le 0.70$ ,  $0.85 \le c \le 1.0$ , and 2a + 3b + 4c = 6, the ceramic composition being free from lead and bismuth; and

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- sintering the multiplayer stack, characterized in that

the glass composition contains a bivalent metal oxide chosen from the group consisting of MgO and ZnO and at least 10% weight with respect to the glass composition of a further metal oxide chosen/from the group consisting of Li<sub>2</sub>O and TiO<sub>2</sub>,

20 - the dielectric composition further contains a metal oxide which is different from the bivalent metal oxide present in the glass composition, and

- the multilayer stack is sintered at a temperature of between 900 and 1080 °C and in an atmosphere which is non-oxidizing for Cu.
- 9. An electronic device comprising a first dielectric ceramic layer, a first electrode comprising Cu, and a second electrode, characterized in that the first dielectric ceramic layer is a sintered body comprising:
  - a ceramic composition containing  $Ba_aRE_bTi_cO_3$ , wherein RE represents a rare earth element, with  $0.05 \le a \le 0.25$ ,  $0.525 \le b \le 0.70$ ,  $0.85 \le c \le 1.0$ , and 2a + 3b + 4c = 6, and free from lead and bismuth,
  - a glass composition comprising SiO<sub>2</sub>, a bivalent metal oxide chosen from the group consisting of MgO and ZnO and at least 10% by weight with respect to the glass composition of a further metal oxide chosen from the group consisting of Li<sub>2</sub>O and TiO<sub>2</sub>, and

a metal oxide which is different from the bivalent metal oxide present in the glass composition.

10. An electroni¢ device as claimed in Claim 9,

5 characterized in that the first dielectric ceramic layer is present as a substrate.

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